SNS COLLEGE OF ENGINEERING

Coimbatore-35
An Autonomous Institution

Accredited by NBA – AICTE and Accredited by NAAC – UGC with 'A+' Grade
Approved by AICTE, New Delhi & Affiliated to Anna University, Chennai

- DEPARTMENT OF ELECTRONICS & COMMUNICATION ENGINEERING

- 19EC505–VLSI DESIGN

- III YEAR/ V SEMESTER

UNIT 2 –COMBINATIONAL LOGIC CIRCUITS

TOPIC – STATIC AND DYNAMIC CMOS DESIGN

OUTLINE

- **STATIC VS DYNAMIC CMOS DESIGN**
- **COMPLEMENTARY CMOS LOGIC GATES**
- **NMOS OPERATION**
- **COMPLEX GATE**
- **DYNAMIC CIRCUIT LOGIC**
- **PRECHARGE & EVALUATE**
- **ACTIVITY**
- **COMPARISON OF CMOS CIRCUITS & EVALUATE CONTD..NMOS OPERATION**
- **ADVANTAGES**
- **DYNAMIC LOGIC PROBLEMS**
- **ASSESSMENT**
- **SUMMARY & THANK YOU**

STATIC VS DYNAMIC CMOS DESIGN

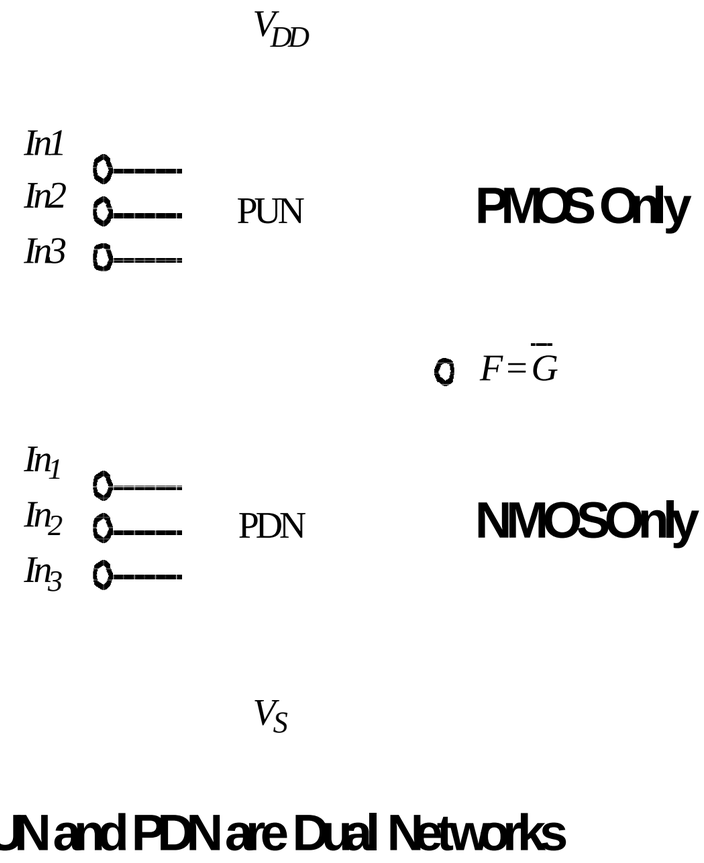
Static

Each gate output have a low resistive path to either V_{DD} or GND

Dynamic

Relies on storage of signal the value in a capacitance

requires high impedance nodes



PUN and PDN are Dual Networks

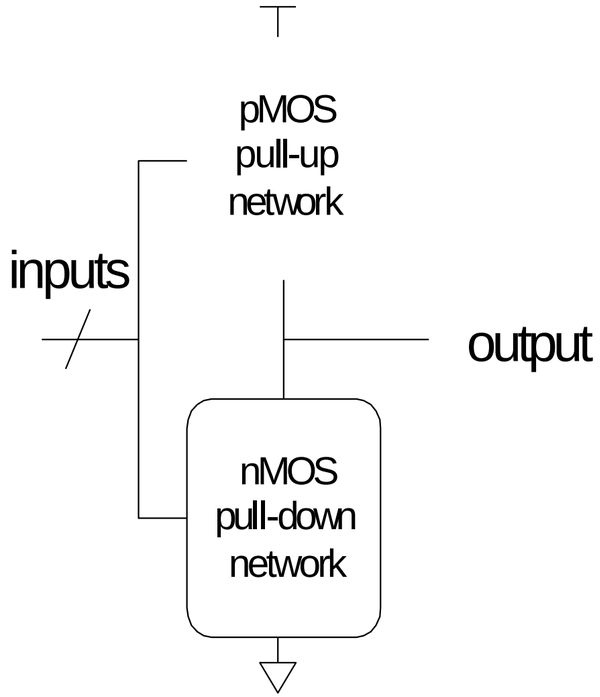
COMPLEMENTARY CMOS LOGIC GATES

–nMOS pull-down network

–pMOS pull-up network

–a.k.a. static CMOS

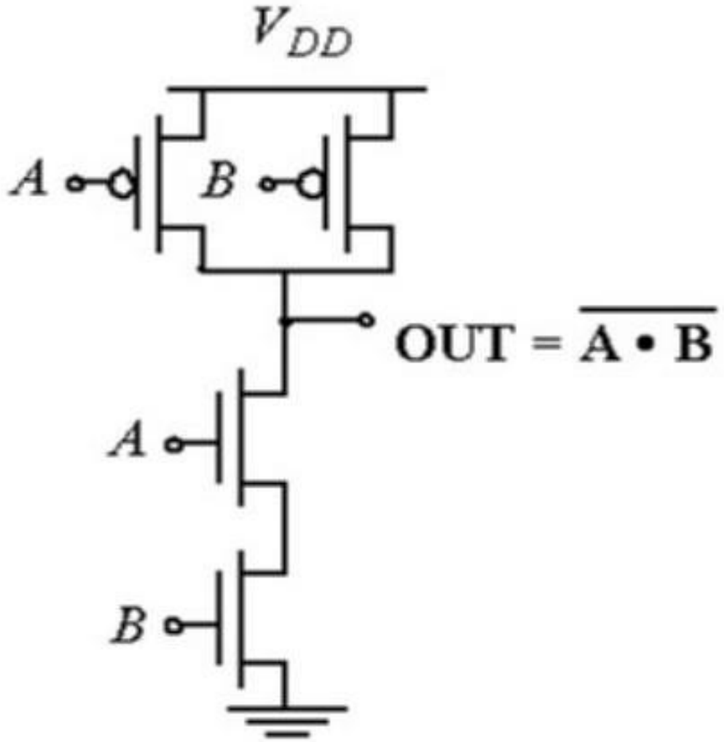
	Pull-up OFF	Pull-up ON
Pull-down OFF	Z (float)	1
Pull-down ON	0	X (crowbar)



EXAMPLE GATE: NAND

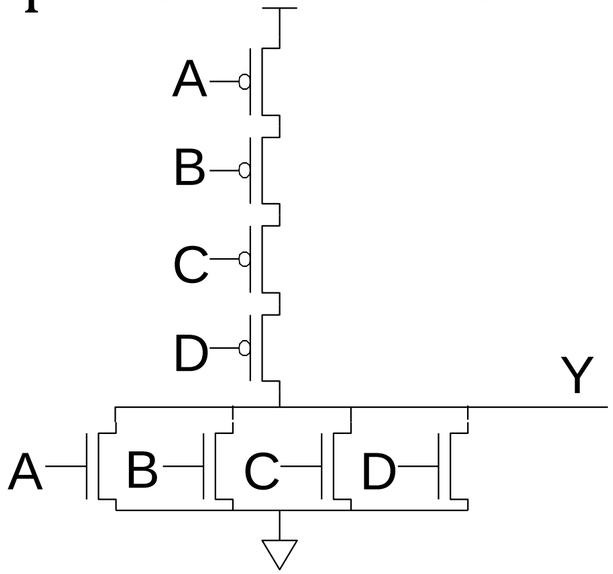
A	B	Out
0	0	1
0	1	1
1	0	1
1	1	0

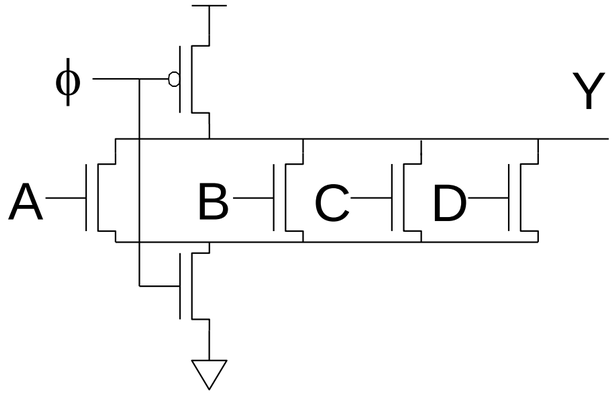
Truth Table of a 2 input NAND gate



DYNAMIC C-MOS LOGIC CIRCUITS-BASIC PRINCIPLES-INTRODUCTION

- Dynamic gates use a clocked pMOS pull-up
- To design high speed cascades
- Some cascades dissipates large amt of power
- Slow pFETs eliminate, clk- used for gate,data syn.
- Complex electric char.





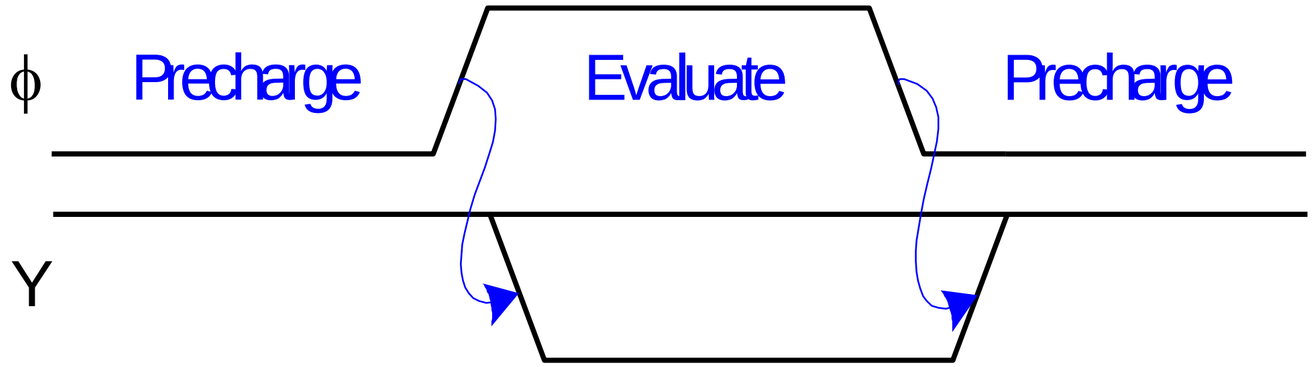
DYNAMIC CIRCUIT LOGIC

Static circuits are slow because fat pMOS load input

Dynamic gates use precharge to remove pMOS transistors from the inputs

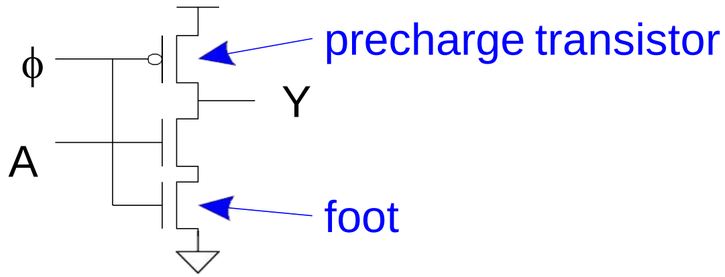
Precharge: f = 0 output forced high

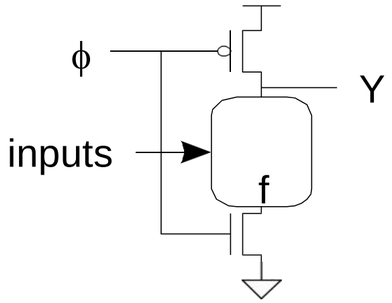
Evaluate: f = 1 output may pull low



THE FOOT

- What if pulldown network is ON during precharge?
- Use series evaluation transistor to prevent fight.





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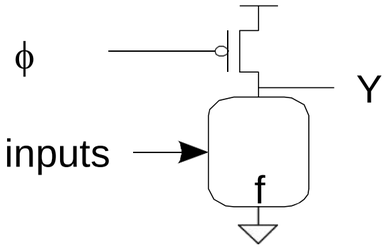

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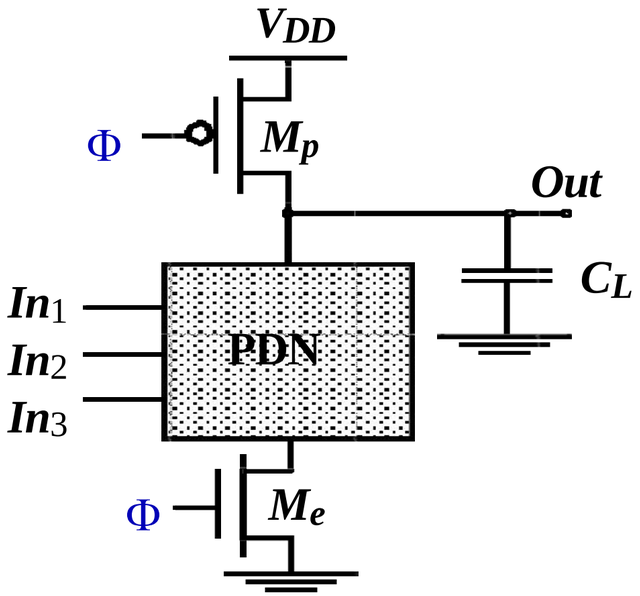
DYNAMIC LOGIC: PRINCIPLES



- **Precharge**: Φ = 0, *Out* is precharged to V_{DD} by M_p. M_e is turned off, no dc current flows (regardless of input values)

- **Evaluation**

  Φ = 1, M_e is turned on, M_p is turned off. Output is pulled down to zero depending on the values on the inputs. If not, pre charged value remains on C_L.

Important: Once *Out* is discharged, it cannot be charged again! Gate input can make only one transition during evaluation

- Minimum clock frequency must be maintained
- Can M_e be eliminated?

PRECHARGE & EVALUATE

It uses single clk ctrl comple.pair-Mp,Mn

Array of nFET-open or closed switch dep. on i/p(any one FET enough for ‘sw’)

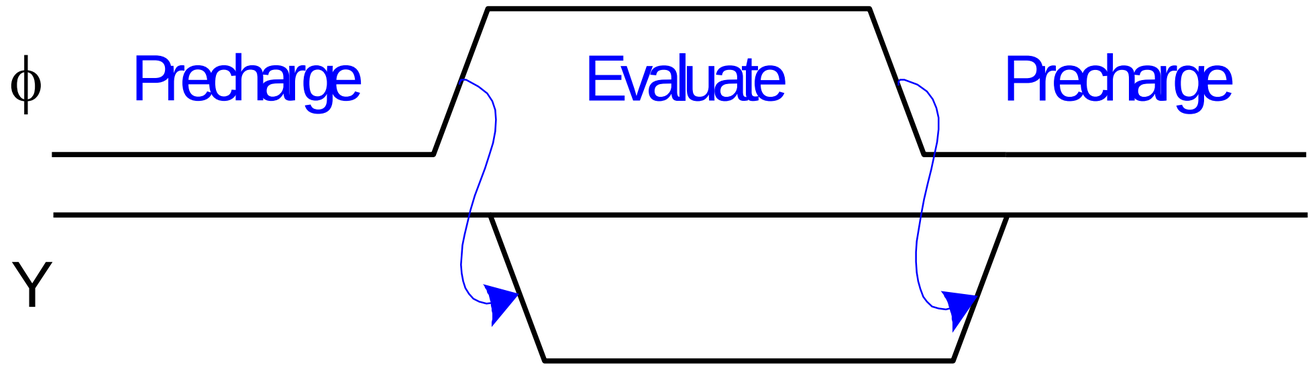
oper. ctrl by clk

Clk=0 →precharge Mp-ON,Mn-OFF

Cout to charge to value Vout=Vdd,every half cycle

Clk=1 →evaluate of the operational cycle

Mp-OFF,Mn-ON.a,b,c accept into nFET logic array



ACTIV
ITY

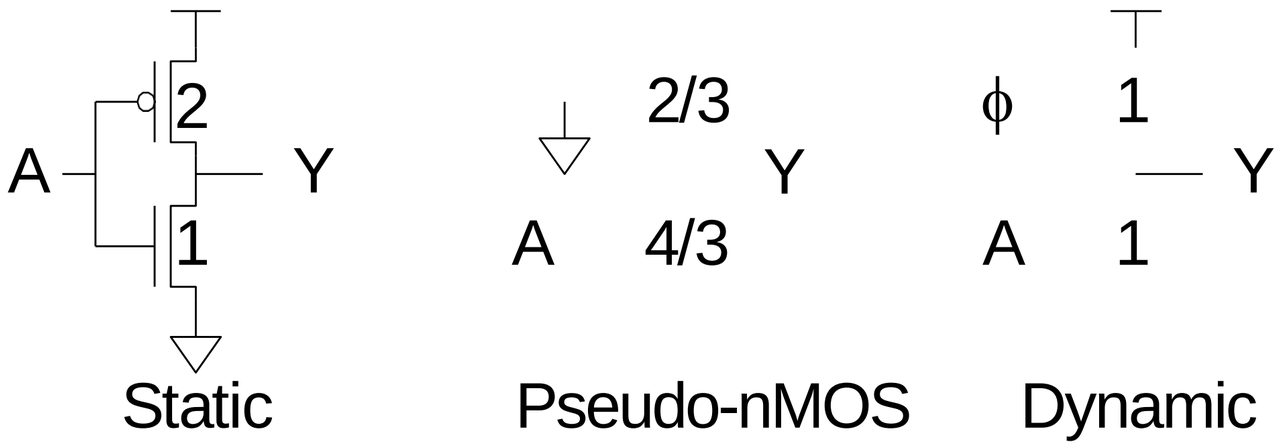
BRAIN TEASER

Look at this series:

7, 10, 8, 11, 9, 12, ...

What number should come next?

COMPARISON OF CMOS CIRCUITS & EVALUATE CONTD..



If array acts open sw →Vout held at Vdd= f=1.

If closed sw→Cout –Vout=0v ,so f=0

*the sequence occurs every clk cycle

Ex:

DYNAMIC NOR2,NAND2 GATES

DYNAMIC LOGIC ADVANTAGES

- To design high speed cascades
- Some cascades dissipates large amt of power
- Slow pFETs eliminate, clk- used for gate,data syn.
- Complex electric char.

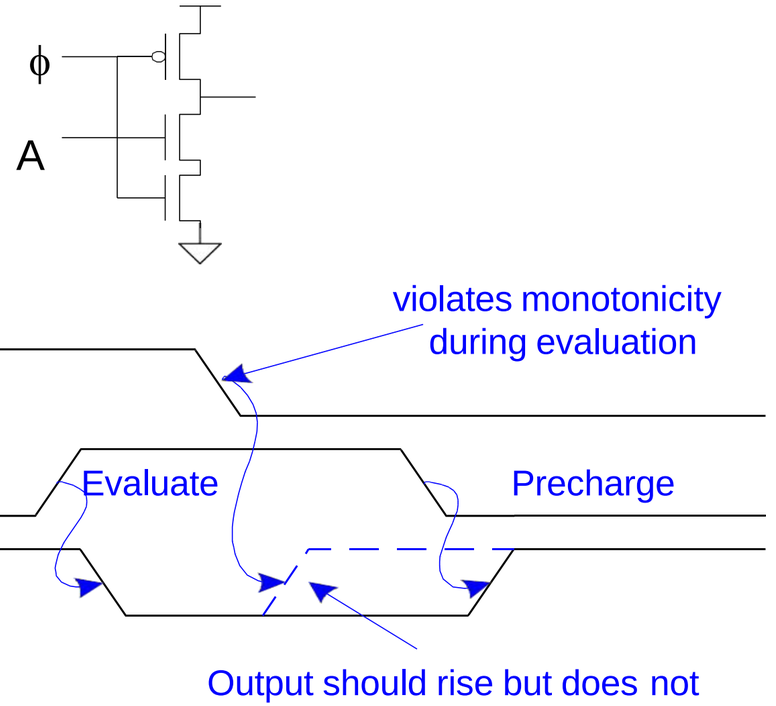
- N+2 transistors for N-input function
  - Better than 2N transistors for complementary static CMOS
  - Comparable to N+1 for ratio-ed logic
- No static power dissipation
  - Better than ratio-ed logic
- Careful design, clock signal needed

DYNAMIC LOGIC PROBLEMS

- Monotonicity
- Charge Leakage
- Charge Sharing
- Capacitive Coupling
- Clock Feed through

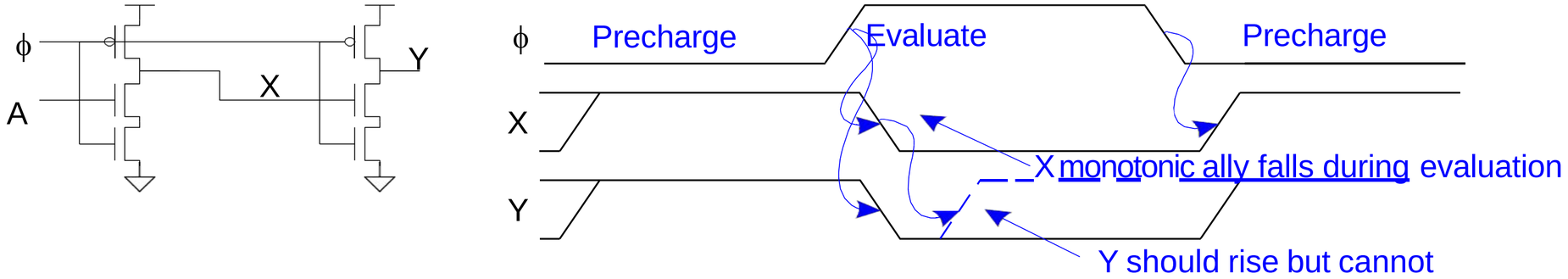
MONOTONICITY

- Dynamic gates require monotonically rising inputs during evaluation
  - 0 -> 0
  - 0 -> 1
  - 1 -> 1
  - But not 1 -> 0

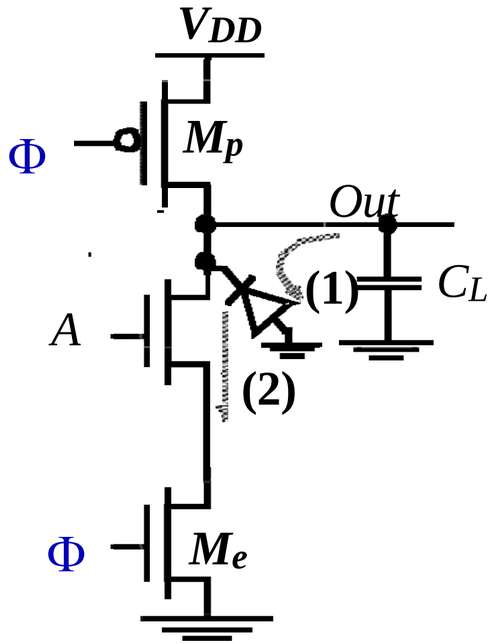


MONOTONICI TY WOES

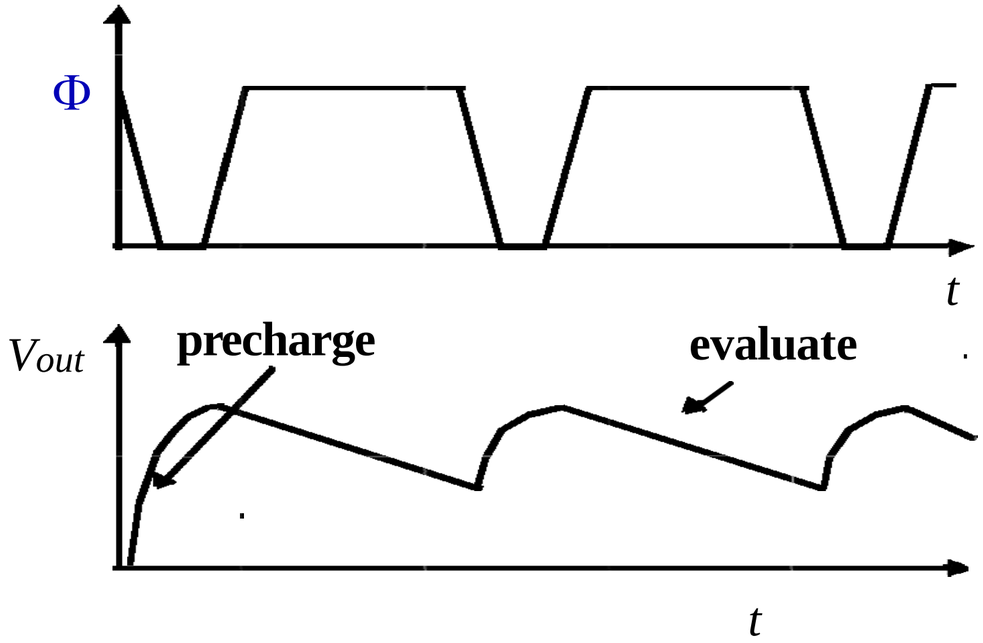
- But dynamic gates produce monotonically falling outputs during evaluation
- Illegal for one dynamic gate to drive another!



RELIABILITY PROBLEMS — CHARGE LEAKAGE



(a)Leakage sources



(b) Effect on waveforms

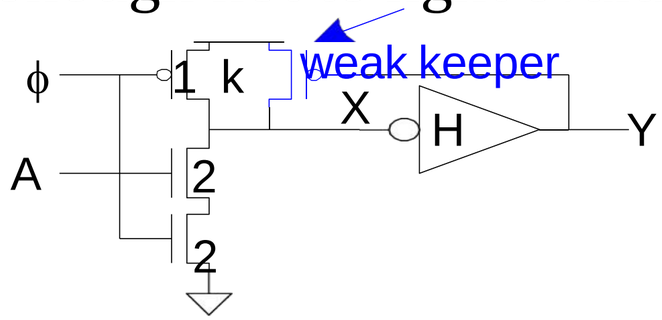
A = 0

(1)Leakage through reverse-biased diode of the diffusion area
(2)Subthreshold current from drain to source

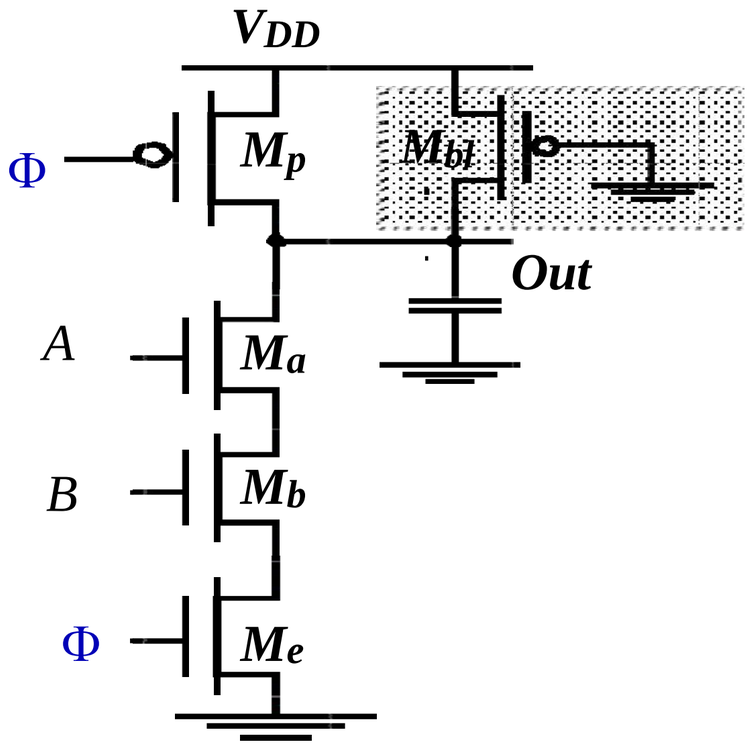
Minimum Clock Frequency: > 1 MHz

LEAKAGE

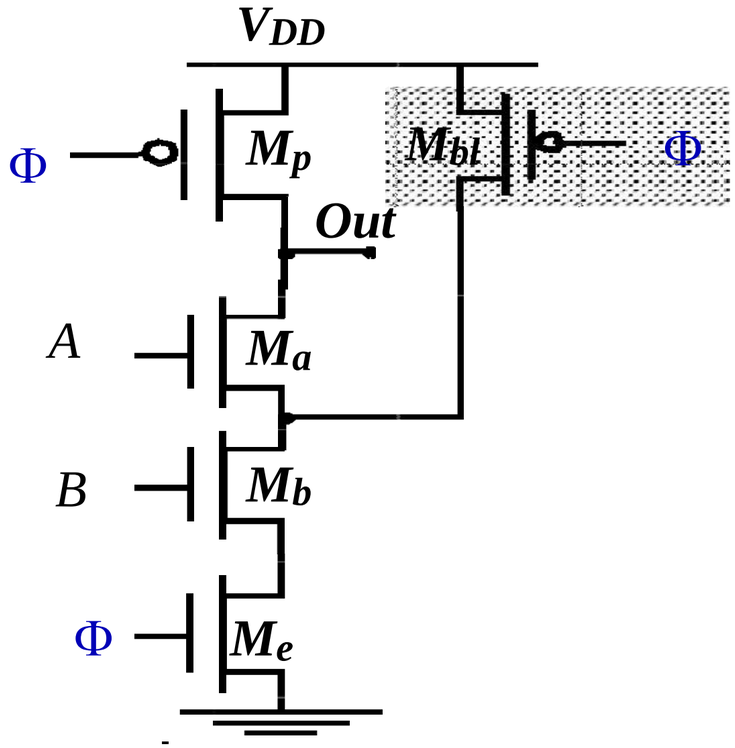
- Dynamic node floats high during evaluation
  - Transistors are leaky (I_{OFF} 0)
  - Dynamic value will leak away over time
  - Formerly miliseconds, now nanoseconds!
- Use keeper to hold dynamic node
  - Must be weak enough not to fight evaluation



CHARGE REDISTRIBUTION - SOLUTIONS



(a) Static bleeder



(b) Precharge of internal nodes

ASSESSMENT

- Compare Static & Dynamic logic
- List out dynamic logic problems
- How monotonicity problem is solved?

SUMMARY &
THANK YOU